

**Notice of References Cited**

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10/689,537

Applicant(s)/Patent Under

Reexamination

TANEDA ET AL.

Examiner

Kiet Doan

Art Unit

2683

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0248625 A1	12-2004	Yoshida et al.	455/575.1
	B	US-2002/0173281	11-2002	Kobayashi, Fumiyuki	455/90
	C	US-2004/0023684 A1	02-2004	Sato et al.	455/550.1
	D	US-6,704,586 B2	03-2004	Park, Jun-Sang	455/575.3
	E	US-2002/0016182	02-2002	Kubo et al.	455/550
	F	US-6,754,507 B2	06-2004	Takagi, Hisamitsu	455/550.1
	G	US-6,751,488 B2	06-2004	Lee, In Ho	455/575.3
	H	US-6,421,547 B1	07-2002	Frohlund et al.	455/575.3
	I	US-2002/0072335 A1	06-2002	Watanabe, Yohsuke	455/90
	J	US-2003/0027590 A1	02-2003	Nakamura et al.	455/550
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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